



# LC321667BJ, BM, BT-70/80

## 1 MEG (65536 Words × 16 Bits) DRAM EDO Page Mode Byte Write

### Preliminary

### Overview

The LC321667BJ series is a CMOS dynamic RAM operating on a single 5 V power source and having a 65536 words × 16 bits configuration. Equipped with large capacity capabilities, high speed transfer rates and low power dissipation, this series is suited for a wide variety of applications ranging from computer main memory and expansion memory to commercial equipment.

Address input utilizes a multiplexed address bus which permits it to be enclosed in a compact plastic package of 40-pin SOJ. Refresh rates are within 4 ms with 256 row address (A0 to A7) selection and support Row Address Strobe ( $\overline{\text{RAS}}$ )-only refresh, Column Address Strobe ( $\overline{\text{CAS}}$ )-before- $\overline{\text{RAS}}$  refresh and hidden refresh settings. There are functions such as Extended Data Out (EDO) page mode, read-modify-write and byte write.

### Features

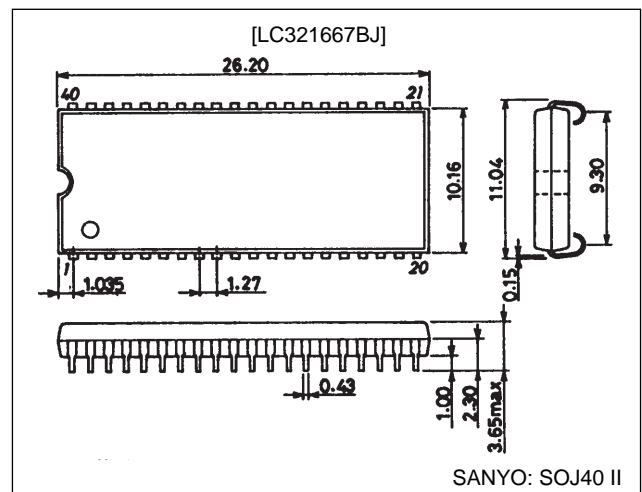
- 65536 words × 16 bits configuration.
- Single 5 V ± 10% power supply.
- All input and output (I/O) TTL compatible.
- Supports EDO page mode, read-modify-write and byte write.
- Supports output buffer control using early write and Output Enable ( $\overline{\text{OE}}$ ) control.

- 4 ms refresh using 256 refresh cycles.
- Supports  $\overline{\text{RAS}}$ -only refresh,  $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$  refresh and hidden refresh.
- Packages  
SOJ 40-pin plastic package (400 mil): LC321667BJ  
SOP 40-pin plastic package (525 mil): LC321667BM  
TSOP 44-pin plastic package (400 mil): LC321667BT
- $\overline{\text{RAS}}$  access time/column address access time/ $\overline{\text{CAS}}$  access time/cycle time/power dissipation.

### Package Dimensions

unit: mm

#### 3200-SOJ40 II



Parameter		LC321667BJ, BM, BT-70	LC321667BJ, BM, BT-80
RAS access time		70 ns	80 ns
Column address access time		40 ns	45 ns
CAS access time		25 ns	25 ns
Cycle time		125 ns	135 ns
Power consumption (max)	During operation	688 mW	633 mW
	During standby	5.5 mW (CMOS level)/11 mW (TTL level)	

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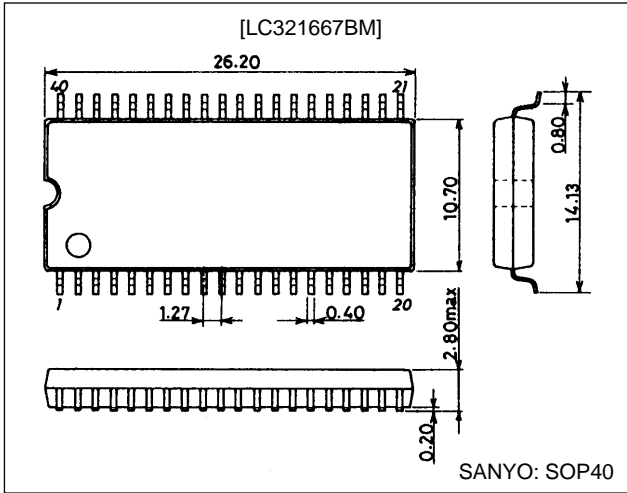
**SANYO Electric Co., Ltd. Semiconductor Business Headquarters**

TOKYO OFFICE Tokyo Bldg., 1-10, 1 Chome, Ueno, Taito-ku, TOKYO, 110-8534 JAPAN

### Package Dimensions

unit: mm

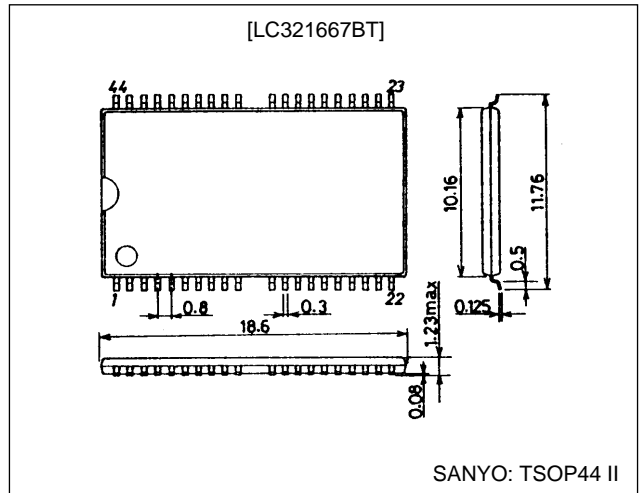
#### 3195-SOP40



### Package Dimensions

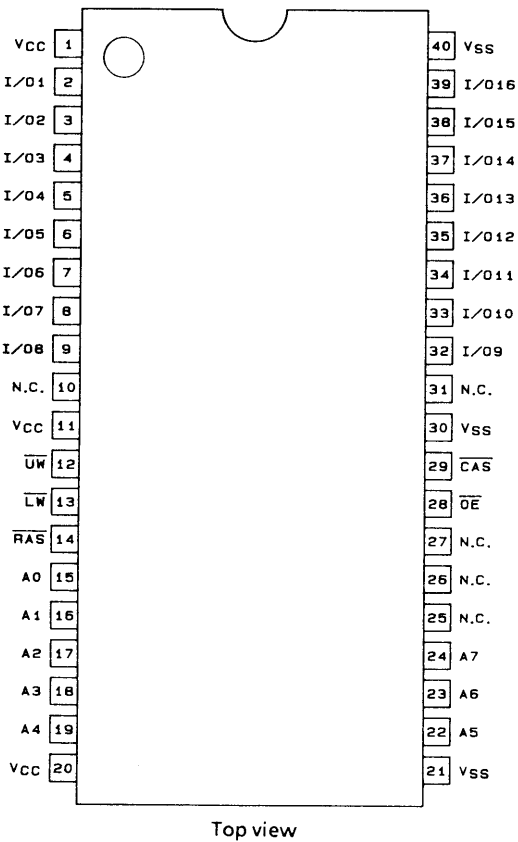
unit: mm

#### 3207-TSOP44 II



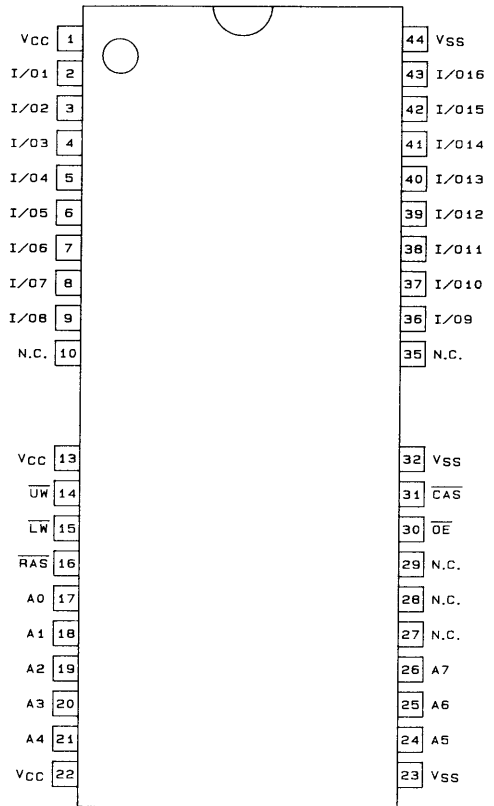
### Pin Assignments

#### SOJ40, SOP40



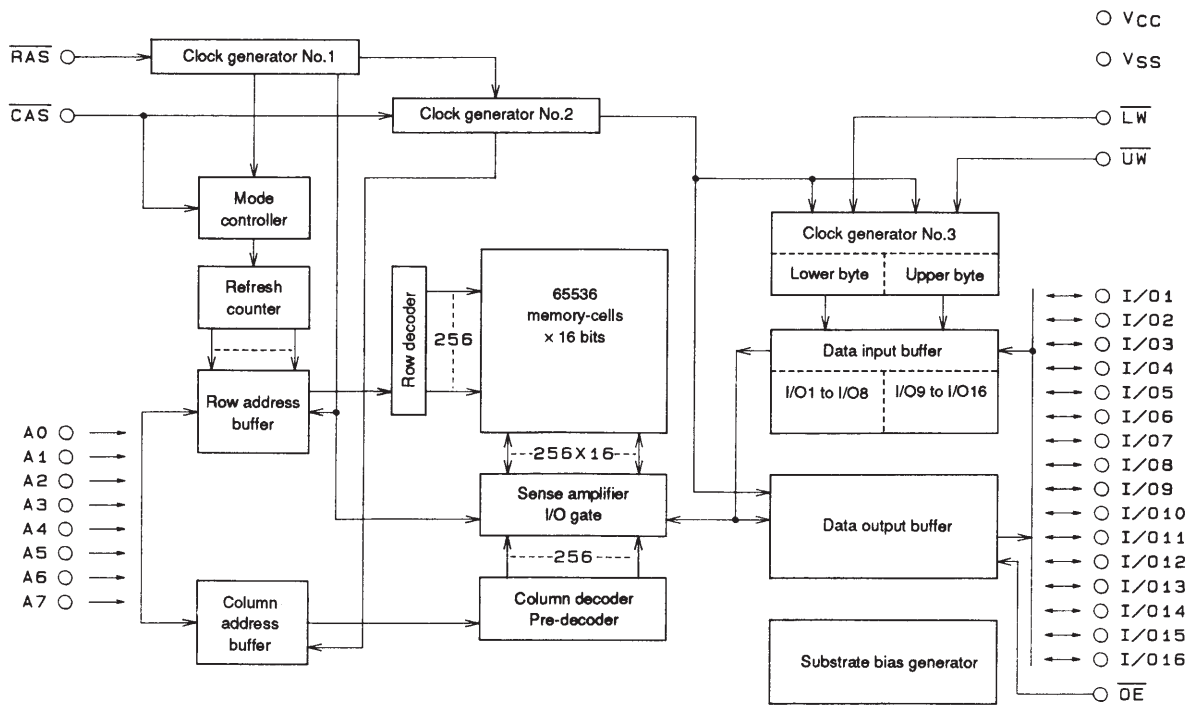
A02123

#### TSOP44



A02943

**Block Diagram**



A02125

**Specifications**

**Absolute Maximum Ratings**

Parameter	Symbol	Ratings	Unit	Note
Maximum supply voltage	$V_{CC\ max}$	-1.0 to +7.0	V	1
Input voltage	$V_{IN}$	-1.0 to +7.0	V	1
Output voltage	$V_{OUT}$	-1.0 to +7.0	V	1
Operating temperature range	$T_{opr}$	0 to +70	°C	1
Storage temperature range	$T_{stg}$	-55 to +150	°C	1
Allowable power dissipation	Pd max	800	mW	1
		700		
Output short-circuit current	$I_{OUT}$	50	mA	1

Note: 1. Stresses greater than the above listed maximum values may result in damage to the device.

**DC Recommended Operating Ranges at  $T_a = 0$  to  $+70^\circ C$**

Parameter	Symbol	min	typ	max	Unit	Note
Power supply voltage	$V_{CC}$	4.5	5.0	5.5	V	2
Input high level voltage	$V_{IH}$	2.4		6.5	V	2
Input low level voltage (A0 to A7, RAS, CAS, $\overline{UW}$ , $\overline{LW}$ , $\overline{OE}$ )	$V_{IL}$	-1.0*1		+0.8	V	2
Input low level voltage (I/O1 to I/O16)	$V_{IL}$	-0.5*1		+0.8	V	2

Note: 2. All voltages are referenced to  $V_{SS}$ .

A bypass capacitor of about 0.1  $\mu F$  should be connected between  $V_{CC}$  and  $V_{SS}$  of the device.

\*1: -2.0 V when pulse width is less than 20 ns.

## LC321667BJ, BM, BT-70/80

### DC Electrical Characteristics at $T_a = 0$ to $+70^\circ\text{C}$ , $V_{CC} = 5\text{ V} \pm 10\%$

Parameter	Symbol	Conditions	LC321667 BJ, BM, BT-70		LC321667 BJ, BM, BT-80		Unit	Note
			min	max	min	max		
Operating current (Average current during operation)	$I_{CC1}$	$\overline{\text{RAS}}$ , $\overline{\text{CAS}}$ , address cycling: $t_{RC} = t_{RC\text{ min}}$		125		115	mA	3, 4, 5
Standby current	$I_{CC2}$	$\overline{\text{RAS}} = \overline{\text{CAS}} = V_{IH}$		2		2	mA	
$\overline{\text{RAS}}$ -only refresh current	$I_{CC3}$	$\overline{\text{RAS}}$ cycling, $\overline{\text{CAS}} = V_{IH}$ : $t_{RC} = t_{RC\text{ min}}$		125		115	mA	3, 5
EDO page mode current	$I_{CC4}$	$\overline{\text{RAS}} = V_{IL}$ , $\overline{\text{CAS}}$ , address cycling: $t_{PC} = t_{PC\text{ min}}$		110		100	mA	3, 4, 5
Standby current	$I_{CC5}$	$\overline{\text{RAS}} = \overline{\text{CAS}} = V_{CC} - 0.2\text{ V}$		1		1	mA	
$\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ refresh current	$I_{CC6}$	$\overline{\text{RAS}}$ , $\overline{\text{CAS}}$ cycling: $t_{RC} = t_{RC\text{ min}}$		125		115	mA	3
Input leakage current	$I_{IL}$	$0\text{ V} \leq V_{IN} \leq 6.5\text{ V}$ , pins other than test pin = $0\text{ V}$	-10	+10	-10	+10	$\mu\text{A}$	
Output leakage current	$I_{OL}$	$D_{OUT}$ disable, $0\text{ V} \leq V_{OUT} \leq 5.5\text{ V}$	-10	+10	-10	+10	$\mu\text{A}$	
Output high level voltage	$V_{OH}$	$I_{OUT} = -2.5\text{ mA}$	2.4		2.4		V	
Output low level voltage	$V_{OL}$	$I_{OUT} = 2.1\text{ mA}$		0.4		0.4	V	

Note: 3. All current values are measured at minimum cycle rate. Since current flows immoderately, if cycle time is longer than shown here, current value becomes smaller.

4.  $I_{CC1}$  and  $I_{CC4}$  are dependent on output loads. Maximum values for  $I_{CC1}$  and  $I_{CC4}$  represent values with output open.

5. Address change is less than or equal to one time during  $\overline{\text{RAS}} = V_{IL}$ . Concerning  $I_{CC4}$ , it is less than or equal to one time during 1 cycle ( $t_{PC}$ ).

### AC Electrical Characteristics at $T_a = 0$ to $+70^\circ\text{C}$ , $V_{CC} = 5\text{ V} \pm 10\%$ (note 6, 7 and 8)

Parameter	Symbol	LC321667BJ, BM, BT-70		LC321667BJ, BM, BT-80		Unit	Note
		min	max	min	max		
Random read or write cycle time	$t_{RC}$	125		135		ns	
Read-write/read-modify-write cycle time	$t_{RWC}$	170		180		ns	
EDO page mode cycle time	$t_{PC}$	35		40		ns	
EDO page mode read-write/read-modify-write cycle time	$t_{PRWC}$	85		90		ns	
$\overline{\text{RAS}}$ access time	$t_{RAC}$		70		80	ns	9, 14, 15
$\overline{\text{CAS}}$ access time	$t_{CAC}$		25		25	ns	9, 14
Column address access time	$t_{AA}$		40		45	ns	9, 15
$\overline{\text{CAS}}$ precharge access time	$t_{CPA}$		45		50	ns	9
Output low-impedance time from $\overline{\text{CAS}}$ low	$t_{CLZ}$	0		0		ns	9
Output buffer turn-off delay time from $\overline{\text{RAS}}$ or $\overline{\text{CAS}}$	$t_{OFF}$	0	20	0	20	ns	10, 17
Rise and fall time	$t_T$	2.5	50	2.5	50	ns	
$\overline{\text{RAS}}$ precharge time	$t_{RP}$	45		45		ns	
$\overline{\text{RAS}}$ pulse width	$t_{RAS}$	70	10000	80	10000	ns	
$\overline{\text{RAS}}$ pulse width for EDO page mode cycle only	$t_{RASP}$	70	100000	80	100000	ns	
$\overline{\text{RAS}}$ hold time	$t_{RSH}$	20		25		ns	
$\overline{\text{CAS}}$ hold time	$t_{CSH}$	60		70		ns	
$\overline{\text{CAS}}$ pulse width	$t_{CAS}$	20	10000	25	10000	ns	
$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ delay time	$t_{RCD}$	20	45	20	55	ns	14
$\overline{\text{RAS}}$ to column address delay time	$t_{RAD}$	15	30	15	35	ns	15
$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ precharge time	$t_{CRP}$	10		10		ns	
$\overline{\text{CAS}}$ precharge time	$t_{CP}$	10		10		ns	
Row address setup time	$t_{ASR}$	0		0		ns	
Row address hold time	$t_{RAH}$	10		10		ns	
Column address setup time	$t_{ASC}$	0		0		ns	
Column address hold time	$t_{CAH}$	15		15		ns	
Column address hold time referenced to $\overline{\text{RAS}}$	$t_{AR}$	50		55		ns	
Column address to $\overline{\text{RAS}}$ lead time	$t_{RAL}$	25		30		ns	
Read command setup time	$t_{RCS}$	0		0		ns	
Read command hold time referenced to $\overline{\text{CAS}}$	$t_{RCH}$	0		0		ns	11
Read command hold time referenced to $\overline{\text{RAS}}$	$t_{RRH}$	0		0		ns	11
Write command hold time	$t_{WCH}$	15		15		ns	
Write command hold time referenced to $\overline{\text{RAS}}$	$t_{WCR}$	50		55		ns	
Write command pulse width	$t_{WP}$	15		15		ns	

Continued on next page.

## LC321667BJ, BM, BT-70/80

Continued from preceding page.

Parameter	Symbol	LC321667BJ, BM, BT-70		LC321667BJ, BM, BT-80		Unit	Note
		min	max	min	max		
Write command to $\overline{\text{RAS}}$ lead time	$t_{\text{RWL}}$	20		20		ns	
Write command to $\overline{\text{CAS}}$ lead time	$t_{\text{CWL}}$	20		20		ns	
Data input setup time	$t_{\text{DS}}$	0		0		ns	12
Data input hold time	$t_{\text{DH}}$	15		15		ns	12
Data input hold time referenced to $\overline{\text{RAS}}$	$t_{\text{DHR}}$	50		55		ns	
Refresh time	$t_{\text{REF}}$		4		4	ms	
Write command setup time	$t_{\text{WCS}}$	0		0		ns	13
$\overline{\text{CAS}}$ to $\overline{\text{UW}}$ or $\overline{\text{LW}}$ delay time	$t_{\text{CWD}}$	45		45		ns	13
$\overline{\text{RAS}}$ to $\overline{\text{UW}}$ or $\overline{\text{LW}}$ delay time	$t_{\text{RWD}}$	90		100		ns	13
Column address to $\overline{\text{UW}}$ or $\overline{\text{LW}}$ delay time	$t_{\text{AWD}}$	60		65		ns	13
CAS precharge $\overline{\text{UW}}$ or $\overline{\text{LW}}$ delay time for 70 EDO page mode cycle only	$t_{\text{CPWD}}$	65		70		ns	13
$\overline{\text{CAS}}$ setup time for CAS-before-RAS	$t_{\text{CSR}}$	10		10		ns	
$\overline{\text{CAS}}$ hold time for CAS-before-RAS	$t_{\text{CHR}}$	10		10		ns	
$\overline{\text{RAS}}$ precharge $\overline{\text{CAS}}$ active time	$t_{\text{RPC}}$	10		10		ns	
$\overline{\text{CAS}}$ precharge time for CAS-before-RAS counter test	$t_{\text{CPT}}$	40		40		ns	
$\overline{\text{RAS}}$ hold time referenced to $\overline{\text{OE}}$	$t_{\text{ROH}}$	15		15		ns	
$\overline{\text{OE}}$ access time	$t_{\text{OEA}}$		25		25	ns	9
$\overline{\text{OE}}$ delay time	$t_{\text{OED}}$	15		15		ns	
$\overline{\text{OE}}$ output buffer turn-off delay time	$t_{\text{O EZ}}$	0	15	0	15	ns	10
$\overline{\text{OE}}$ command hold time	$t_{\text{OEH}}$	20		20		ns	
$\overline{\text{OE}}$ setup time to $\overline{\text{CAS}}$ high	$t_{\text{OCH}}$	5		5		ns	16
$\overline{\text{OE}}$ hold time from $\overline{\text{CAS}}$ high	$t_{\text{CHO}}$	10		10		ns	16
$\overline{\text{OE}}$ command pulse width	$t_{\text{OEP}}$	10		10		ns	
Data output hold time	$t_{\text{DOH}}$	5		5		ns	
$\overline{\text{WE}}$ output buffer turn-off delay time	$t_{\text{WEZ}}$	0	15	0	15	ns	
Data input to $\overline{\text{CAS}}$ delay time	$t_{\text{DZC}}$	0		0		ns	16
Data input to $\overline{\text{OE}}$ delay time	$t_{\text{DZO}}$	0		0		ns	16
Masked write setup time	$t_{\text{MCS}}$	0		0		ns	
Masked write hold time referenced to $\overline{\text{RAS}}$	$t_{\text{MRH}}$	0		0		ns	
Masked write hold time referenced to $\overline{\text{CAS}}$	$t_{\text{MCH}}$	0		0		ns	

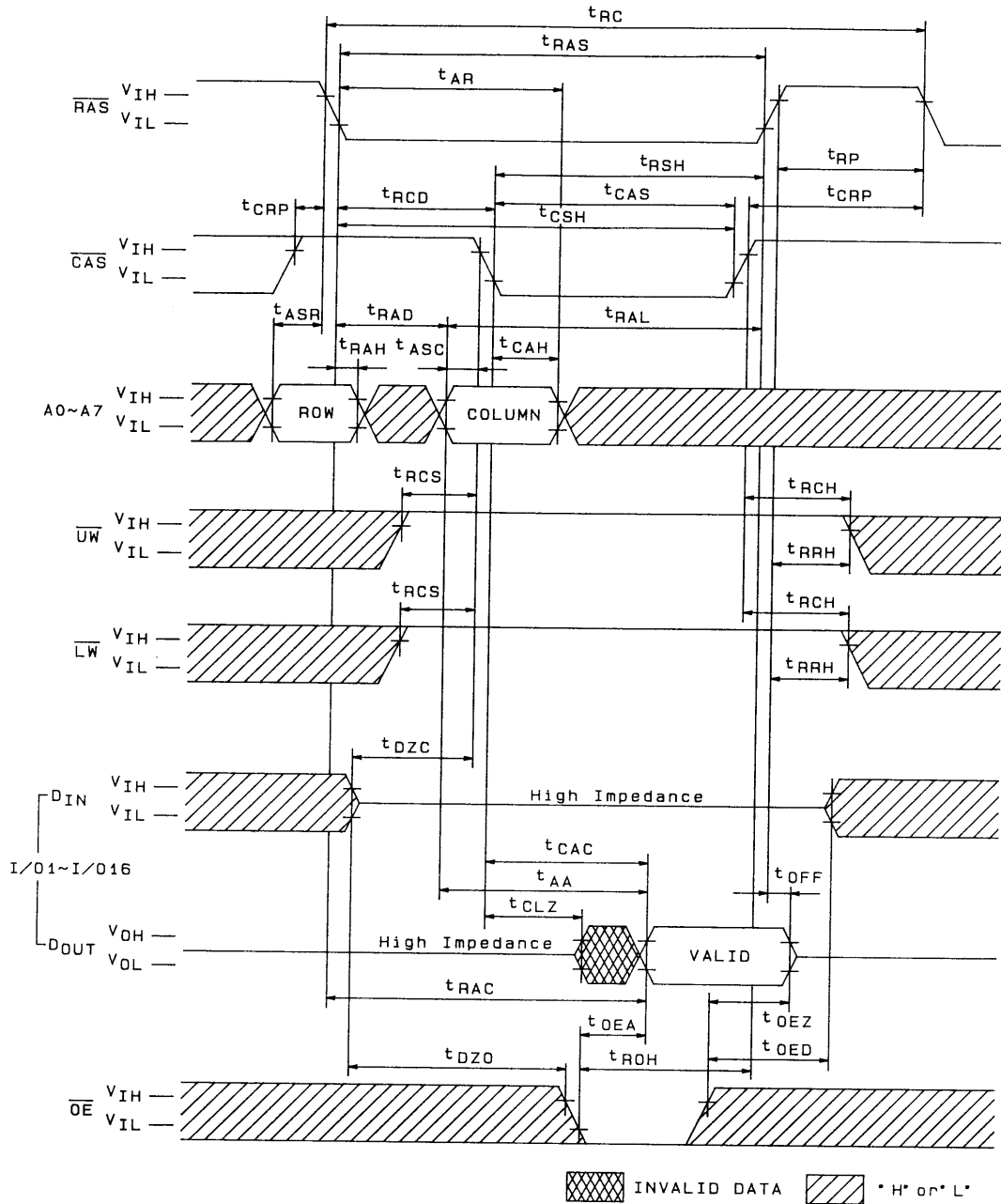
### Input/Output Capacitance at $T_a = 25^\circ\text{C}$ , $f = 1\text{ MHz}$ , $V_{\text{CC}} = 5\text{ V} \pm 10\%$

Parameter	Symbol	min	max	Unit	Note
Input capacitance (A0 to A7, $\overline{\text{RAS}}$ , $\overline{\text{CAS}}$ , $\overline{\text{UW}}$ , $\overline{\text{LW}}$ , $\overline{\text{OE}}$ )	$C_{\text{IN}}$		7	pF	
Input/Output capacitance (I/O1 to I/O16)	$C_{\text{I/O}}$		7	pF	

- Note: 6. An initial pause of 200  $\mu\text{s}$  is required after power-up followed by eight  $\overline{\text{RAS}}$ -only refresh cycles before proper device operation is achieved. In case of using refresh counter, a minimum of eight CAS-before- $\overline{\text{RAS}}$  refresh cycles instead of eight  $\overline{\text{RAS}}$ -only refresh cycles are required.
7. Measured at  $t_{\text{T}} = 2.5\text{ ns}$ .
8. When measuring input signal timing,  $V_{\text{IH}}$  (min) and  $V_{\text{IL}}$  (max) are used for reference points. In addition, rise and fall time are defined between  $V_{\text{IH}}$  and  $V_{\text{IL}}$ .
9. Measured using an equivalent of 50 pF and one standard TTL loads.
10.  $t_{\text{OFF}}$  (max) and  $t_{\text{O EZ}}$  (max) are defined as the time until output voltage can no longer be measured when output switches to a high impedance condition.
11. Operation is guaranteed if either  $t_{\text{RRH}}$  or  $t_{\text{RCH}}$  is satisfied.
12. These parameters are measured from the falling edge of  $\overline{\text{CAS}}$  for an early-write cycle, and from the falling edge of  $\overline{\text{UW}}$  and  $\overline{\text{LW}}$  for a read-write/read-modify-write cycle.
13.  $t_{\text{WCS}}$ ,  $t_{\text{CWD}}$ ,  $t_{\text{RWD}}$ ,  $t_{\text{AWD}}$  and  $t_{\text{CPWD}}$  are not restrictive operating parameters for memory in that they specify the operating mode. If  $t_{\text{WCS}} \geq t_{\text{WCS}}$  (min), the cycle switches to an early-write cycle and output pins switch to high impedance throughout the cycle. If  $t_{\text{CWD}} \geq t_{\text{CWD}}$  (min),  $t_{\text{RWD}} \geq t_{\text{RWD}}$  (min),  $t_{\text{AWD}} \geq t_{\text{AWD}}$  (min) and  $t_{\text{CPWD}} \geq t_{\text{CPWD}}$  (min) for fast page mode cycle only, the cycle switches to a read-write/read-modify-write cycle and data output equal information in the selected cells. If neither of the above timings are satisfied, output pins are in an undefined state.
14.  $t_{\text{RCD}}$  (max) is not a restrictive operating parameter but instead represents the point at which the access time  $t_{\text{RAC}}$  (max) is guaranteed. If  $t_{\text{RCD}} \geq t_{\text{RCD}}$  (max), access time is determined according to  $t_{\text{CAC}}$ .
15.  $t_{\text{RAD}}$  (max) is not a restrictive operating parameter but instead represents the point at which the access time  $t_{\text{RAC}}$  (max) is guaranteed. If  $t_{\text{RAD}} \geq t_{\text{RAD}}$  (max), access time is determined according to  $t_{\text{AA}}$ .
16. Operation is guaranteed if either  $t_{\text{DZC}}$  or  $t_{\text{DZO}}$  is satisfied.
17.  $t_{\text{OFF}}$  is referenced from the rising edge of  $\overline{\text{RAS}}$  or  $\overline{\text{CAS}}$ , whichever occurs last.

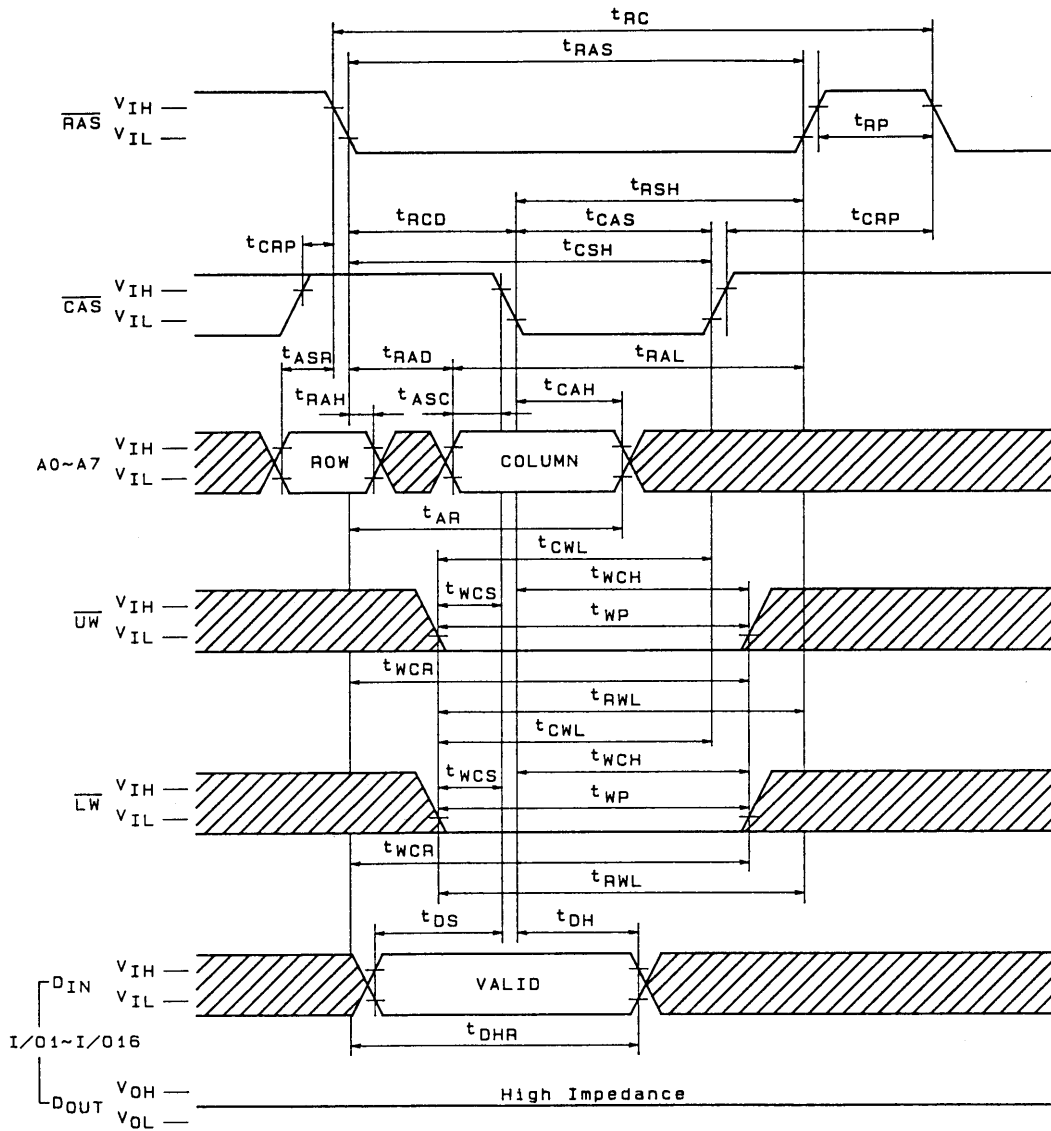
Timing Chart

Read Cycle



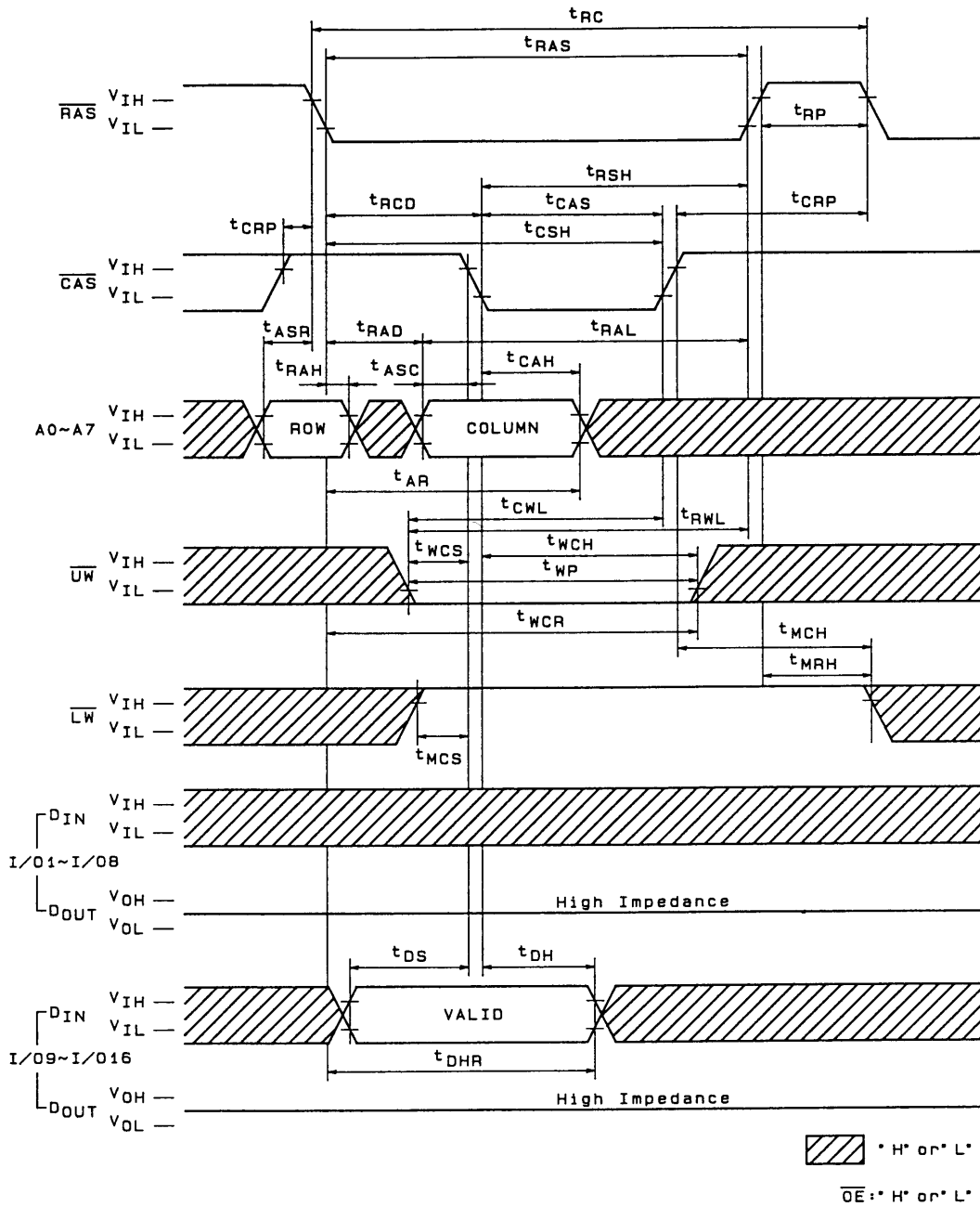
A03721

Early Write Cycle



A02140

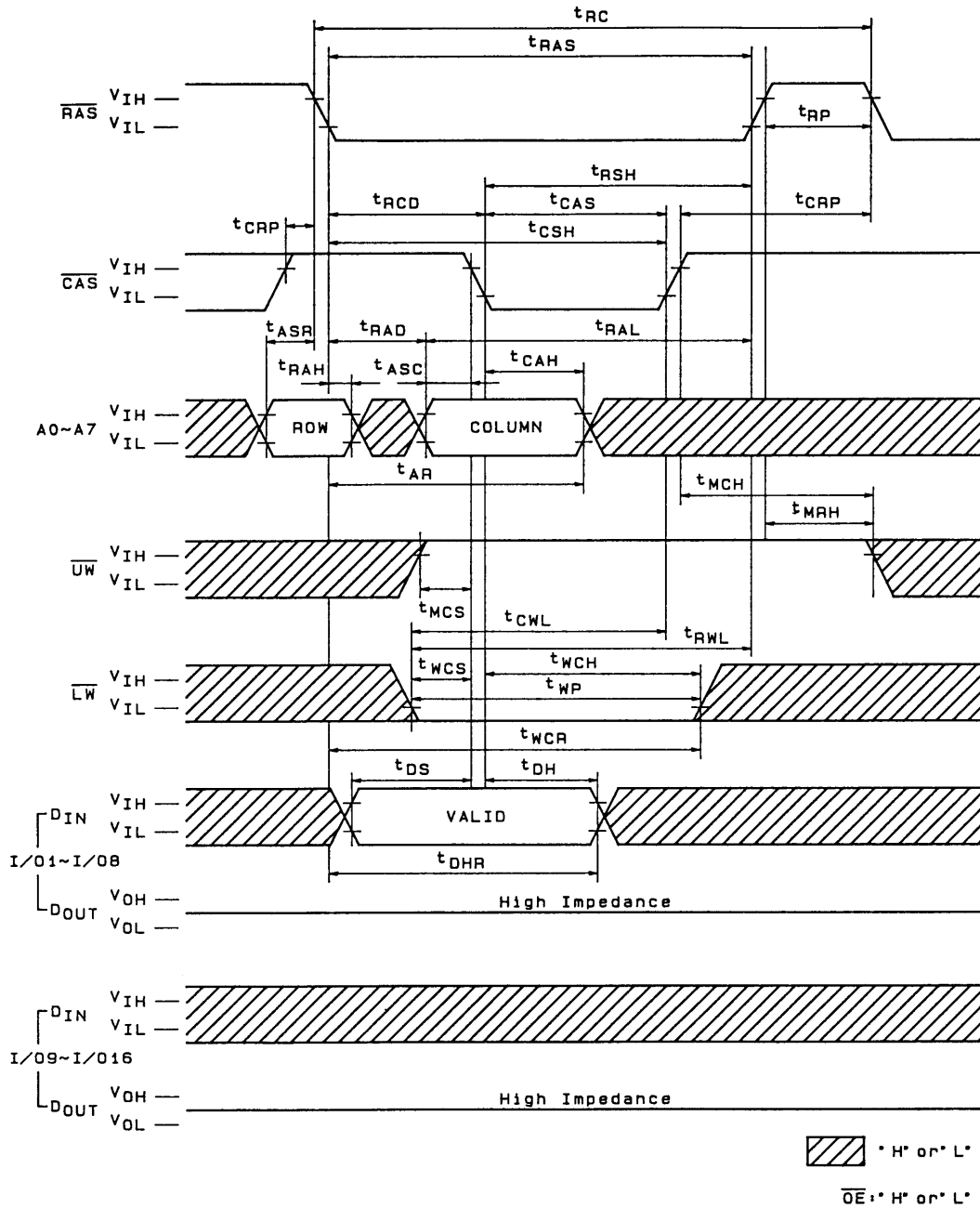
Upper Byte Early Write Cycle



A02141

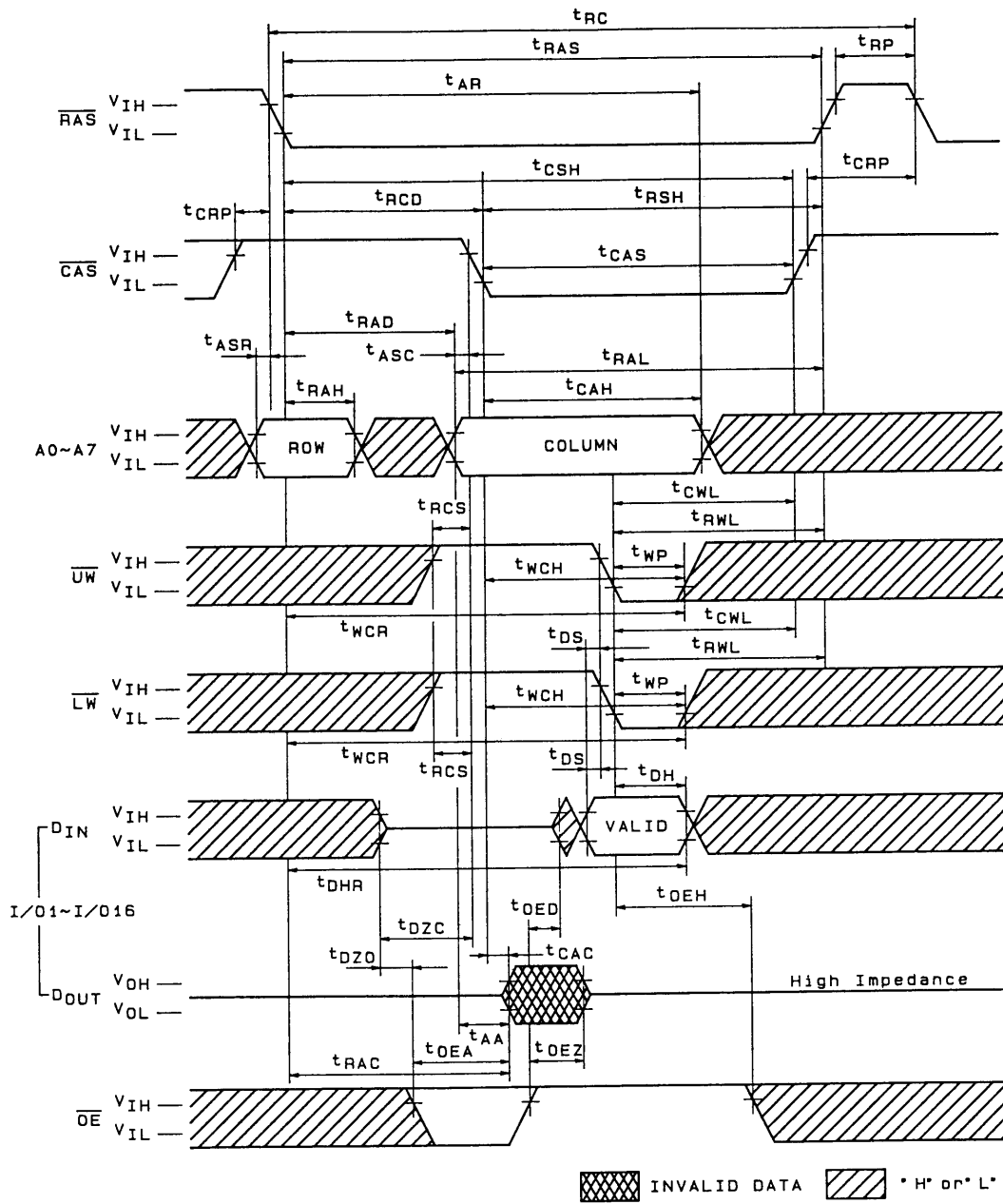


Lower Byte Early Write Cycle



A02142

Write Cycle ( $\overline{OE}$  Control)

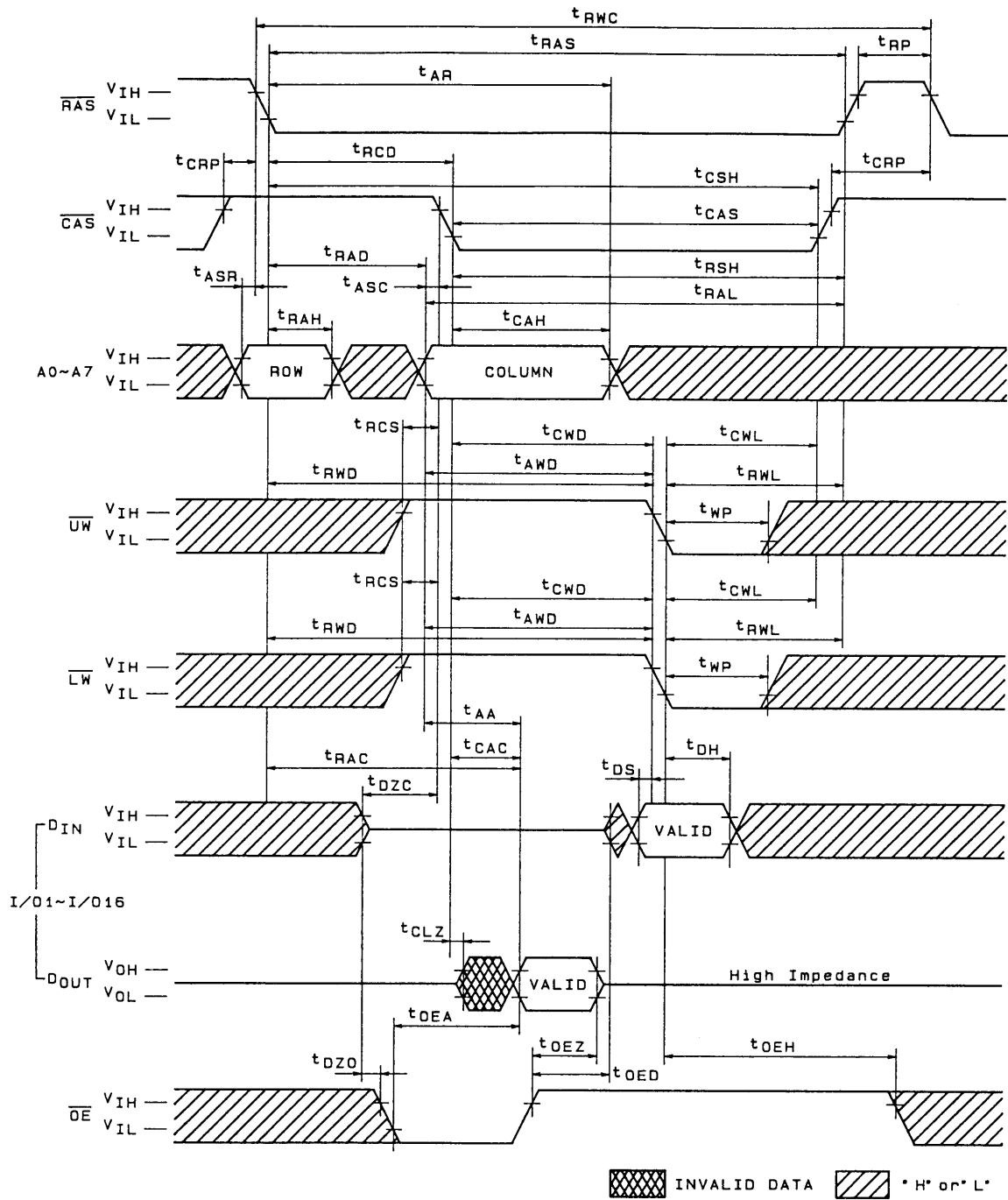


A02143





Read-Modify Write Cycle



A02146



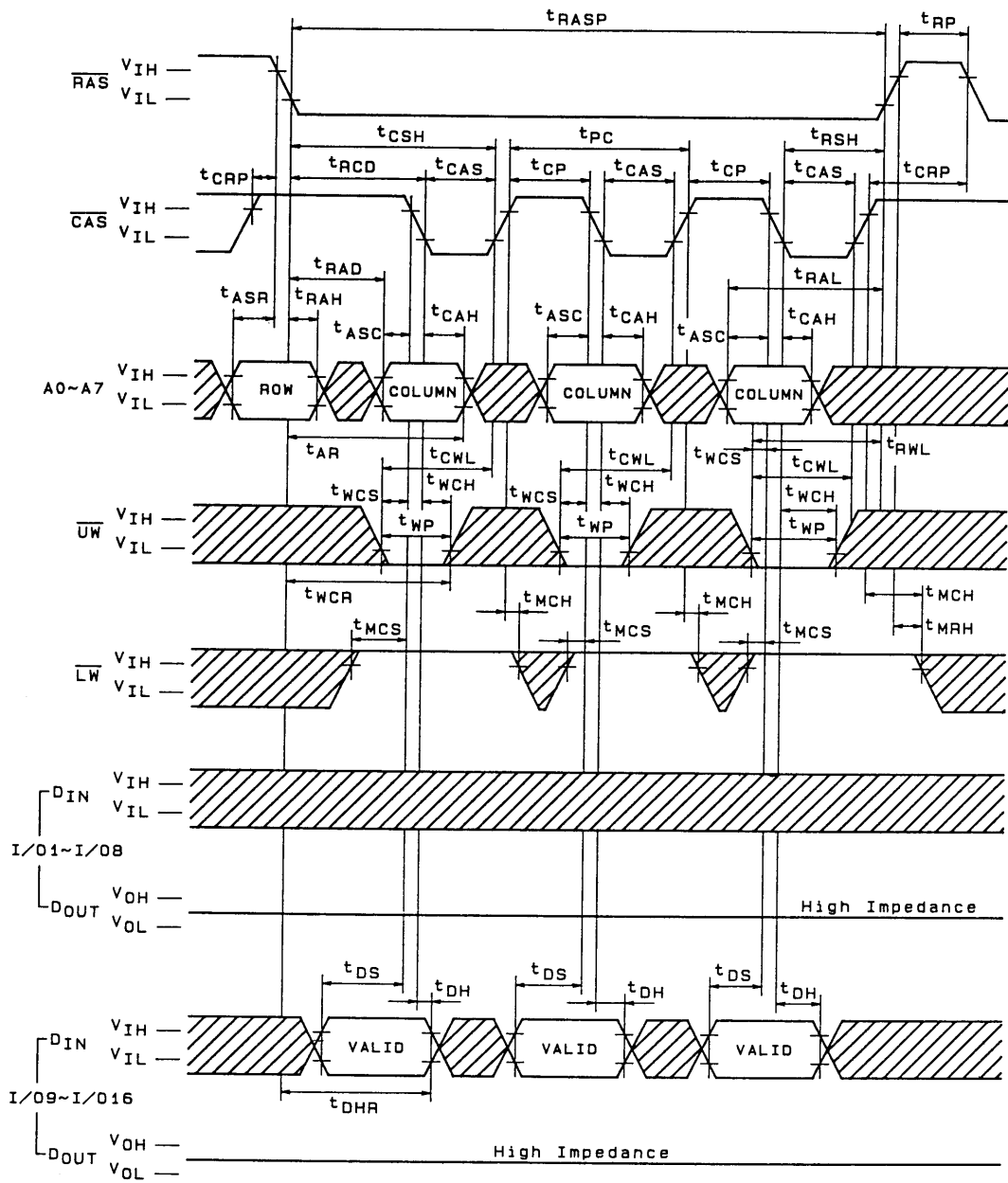








EDO Page Mode Upper Byte Early Write Cycle



\* H\* or\* L\*

$\overline{OE}$ : \* H\* or\* L\*

A02151

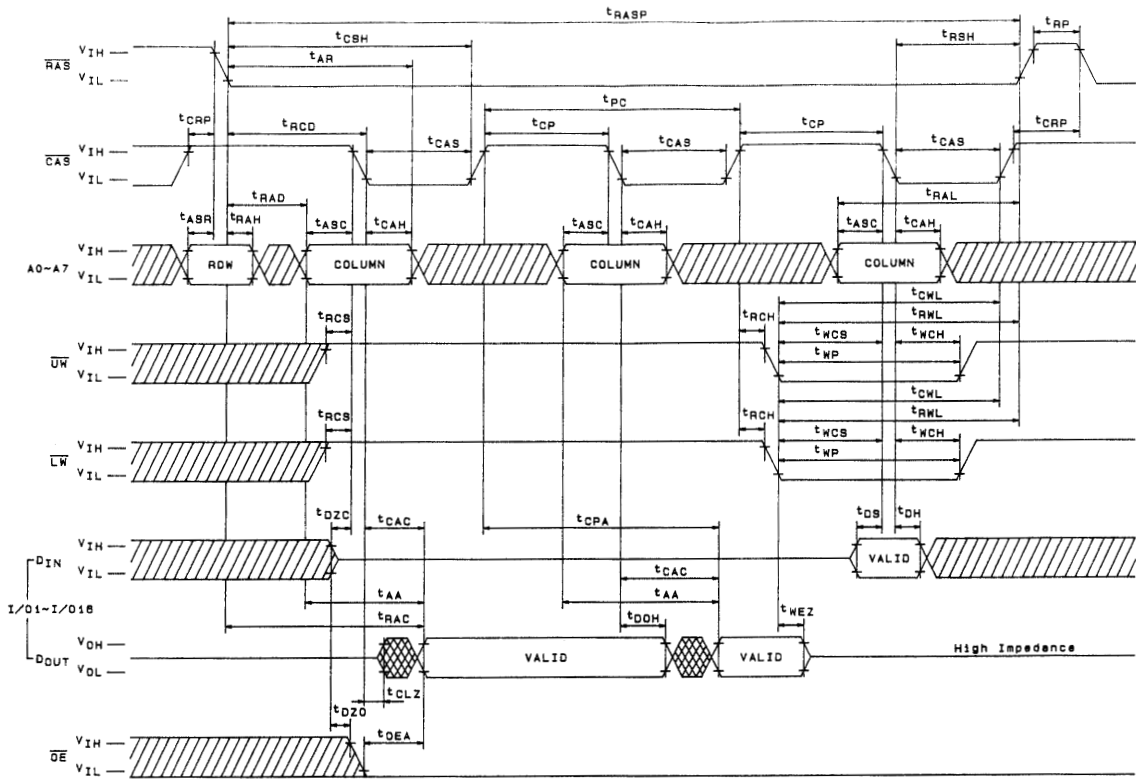








EDO Page Mode Read Early Write Cycle



INVALID DATA 'H' or 'L'

A04088

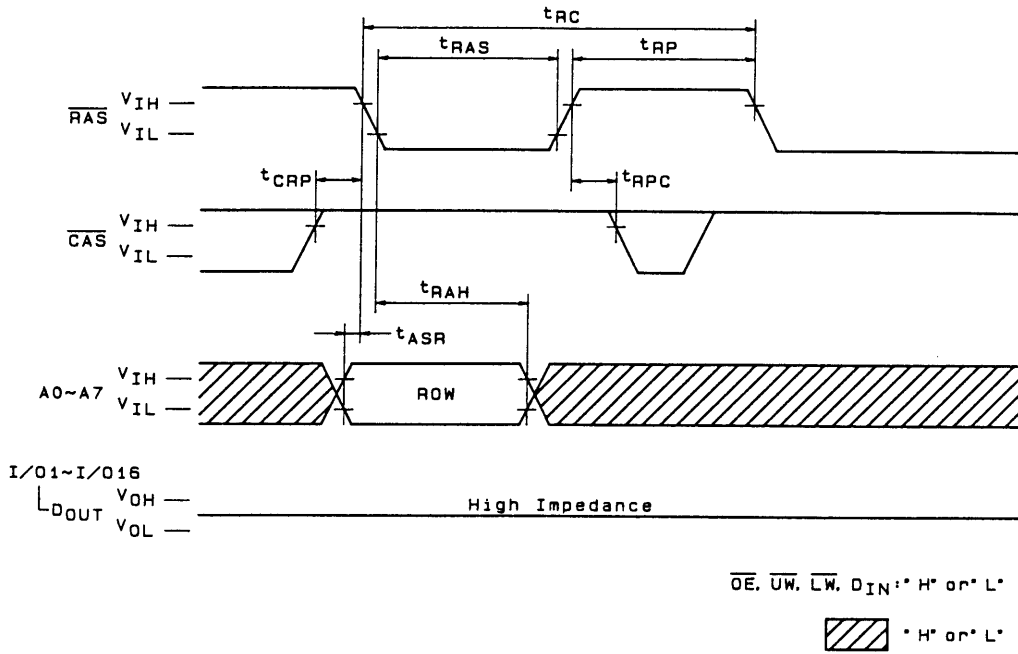






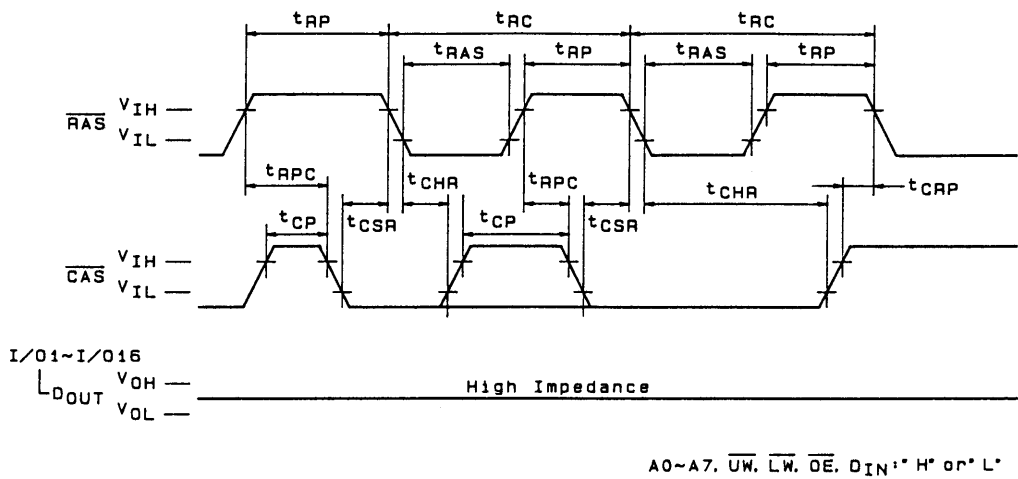


RAS-Only Refresh Cycle



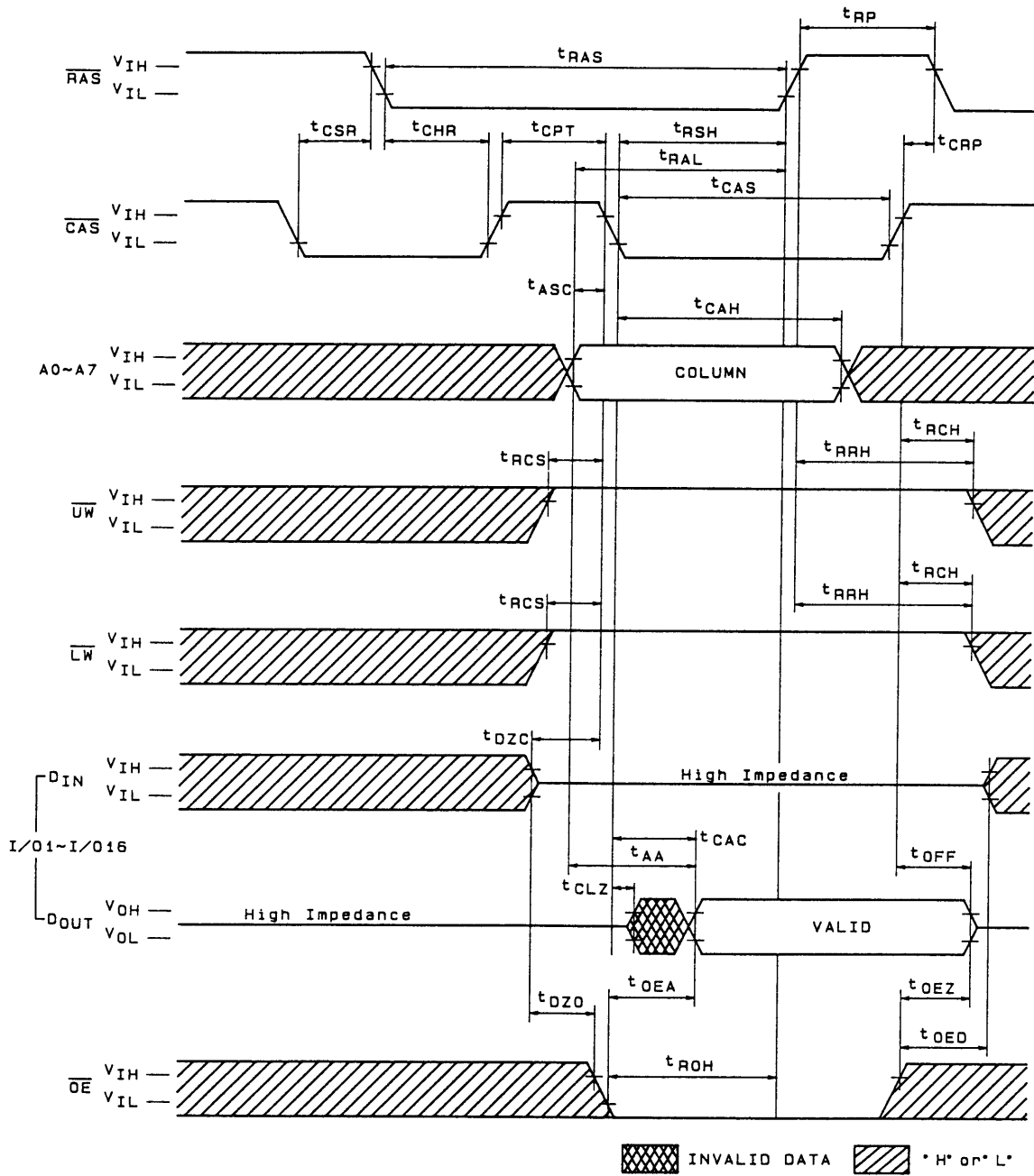
A02157

CAS-Before-RAS Refresh Cycle



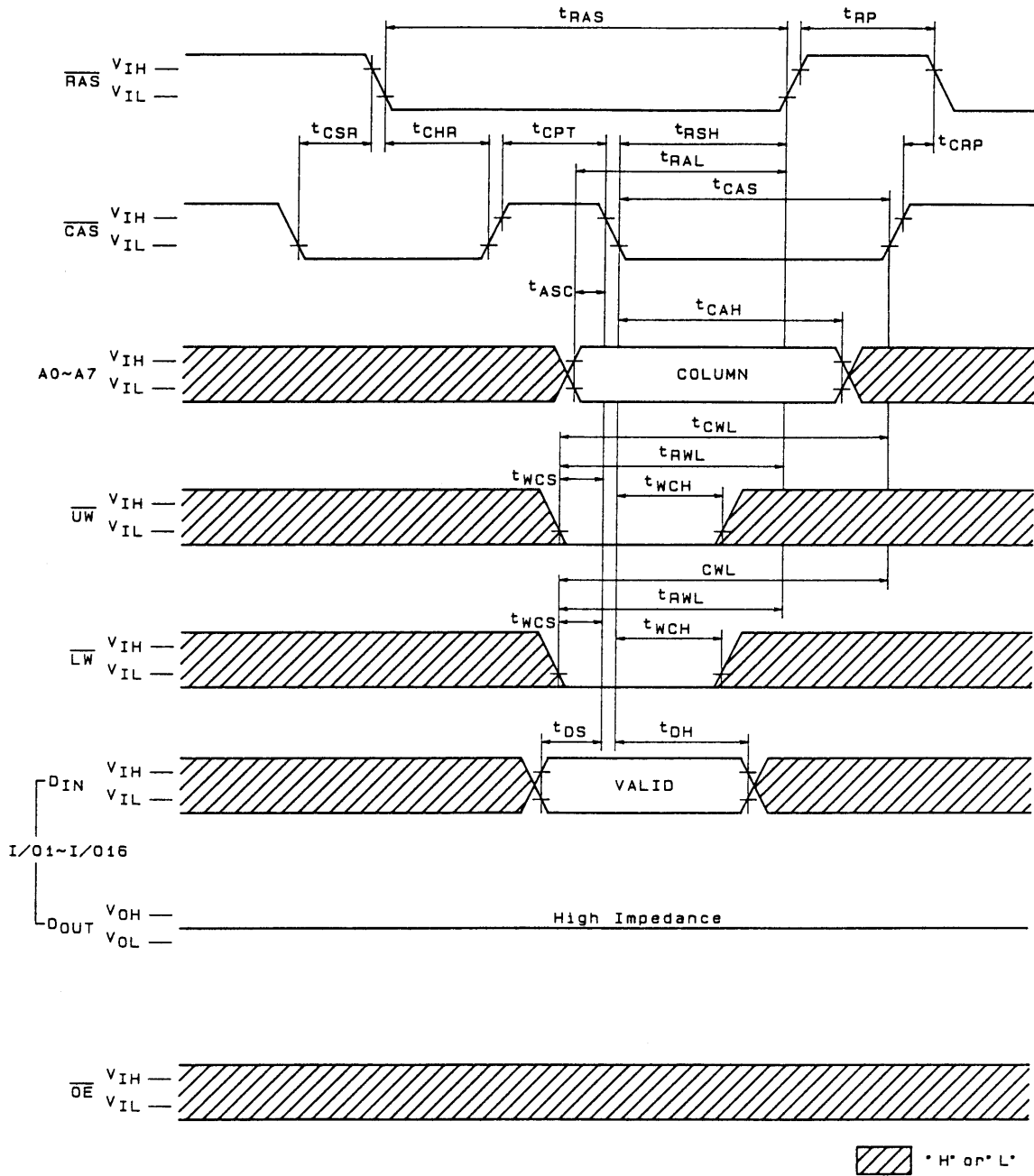
A02158

CAS-Before-RAS Refresh Counter Test Cycle (Read)



A02159

CAS-Before-RAS Refresh Counter Test Cycle (Write)



A02160



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